

<b>Notice of References Cited</b>	Application/Control No. 09/875,716	Applicant(s)/Patent Under Reexamination VIDHANI ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,128,769	10-2000	Carlson et al.	716/6
	B	US-6,499,131	12-2002	Savithri et al.	716/5
	C	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Chen et al., Towards True Crosstalk Noise Analysis, IEEE, 1999
	V	Chen et al., Switching Window Computation for Static Timing Analysis in Presence of Crosstalk Noise, 11/2000
	W	Chen et al., Aggressor alignment for worst-case coupling noise, ACM, 2000
	X	Gross et al., Determination of Worst-Case Aggressor Alignment for Delay Calculation, ACM, 1998

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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	V	Dartu, Calculating Worst-Case Gate Delays Due to Dominant Capacitance Coupling, ACM, 1997
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